

FISCHERSCOPE® X-RAY XDV®-SDD

Built to last: Robust design for particularly high requirements

Fully automatable: Let your instrument work for you with just one click

Quick-measure design: With a few simple steps the sample is placed and ready for measurement. Automated measurements of many parts are possible



DPP+ digital pulse processor: Fast and precise measurement results

RoHS Analysis: Determination of pollutants with high detection accuracy and outstanding performance

Fast: Thanks to short measuring times, you save valuable time



Pollutant analysis of toys

The high-end all-rounder

FISCHERSCOPE® X-RAY XDV®-SDD models are among the most powerful X-ray instruments. Their silicon drift detector is extremely sensitive to fluorescence radiation of light elements. This permits very low detection limits as well as measurement applications relating to NiP, RoHS and very thin layers <math><0.05 \mu\text{m}</math>. This is why the universal XDV®-SDD instrument performs exceedingly well in research and development, laboratory and process qualification settings. Also, its ease of use makes it indispensable in production control.



NiP/Fe: P concentration and layer thickness



Passivation layers: Cr/Zn/Fe

The XDV®-SDD system is especially well suited for precise trace analysis and rapid monitoring of pollutant limit values. For example, in plastics it can be used to determine critical chemical elements such as lead, mercury and cadmium with detection limits of just a few ppm.

Features

- Universal instrument for the determination of pollutants in the smallest concentrations according to RoHs and for automated measurements of layers, including <math><0.05 \mu\text{m}</math>
- Stepless measuring distance with measuring top down
- Microfocus tube with tungsten anode
- 4-fold changeable apertures
- 6-fold changeable filter
- Silicon drift detector 50 mm^2 for highest precision on thin layers
- Aperture (collimator) up to 3 mm: Highest intensity for shortest measuring time even with difficult samples (thinnest coatings, Si wafers, conversion layers), light elements (fuel cells, Al components)
- Programmable measuring stage for automated measurements on small structures
- Fully protected instrument with type approval according to current radiation protection legislation